

Recap

- dimensionality reduction (PCA), clustering (k-means)
- PCA : $f(x) = \mu + V\lambda$ we estimate μ and V from data.
 - $\hat{\mu} = \bar{x}_i$ V = Eigen vector matrix of covariance matrix X
 - $X_{N \times d} \rightarrow Y_{N \times q}$ (should be a diagonal covariance matrix)
- clustering using k-means


```

        assignment
        ↓
        template update → set of templates,
        group assignments
      
```

Modeling: Selection, fitting, and validation

- selection: linear (vs) exponential model
- $$y = aT + b \quad (M_1)$$
- $$= b \exp(-aT) \quad (M_2)$$
- } prior knowledge, or by visual inspection
- space filling design spanning T and p^H and computed reaction yield
 - 1. look at the data to identify trends that can help model selection
 - hypothesis class
 - eg: $y = aT + b$
 $= aT + bT^2 + c$ } polynomials
 \vdots
 - Bayesian model selection.

two or more models: M_1, M_2, \dots

$$p((x=(T, p^H), y=y | M_1))$$

$$\propto M_1$$

Bayes factor / simply look at likelihoods
 - fitting/training: find parameters of our parametric models.
 - by some form of minimization of a loss function
$$\ell = \sum_i |y_i - f(x_i)|^2$$
 - model
$$f(T, p^H) = b \exp(-aT) \quad (a, b)^T$$

$$\ell = ((a, b) - f(p))$$

eg: thermal history of 3D printed materials
 - ML and other advance techniques allows us to use arbitrary loss function, automatic diff to perform stochastic gradient descent.
 - data driven modeling: universal function approximator $f(x) = W^T \sigma(x) + b$ — any continuous function using this deep network.
 - no free lunch — not every model will be able to explain the data you have.
 - train data, validation data, test data.
 - data using any of DOE methods we discussed
 - train
 - val
 - test

(DOE) (DOE) (DOE) ← expt (high accuracy)
 ← 2 expt (most usefulness)

every time you run an expt → "distribution shift"

- "sweet spot" high training accuracy high validation accuracy.
- $y \rightarrow (T, p^H)$
- $p(y | T, p^H) = \mu_y + \varepsilon \sim N(0, \sigma^2_y)$ (probabilistic model)

bias, variance and noise from the data itself represent your data errors in expt that are not captured.
- Variance: "overspecified" your model is to the data
- bias: particular parameters that were selected as solution.
- low variance, low bias
- High variance, high bias

How do we actively collect datasets: active learning (probabilistic model, decision theory), model to be accurate enough to give you the optimum: Bayesian optimization.

prediction but also uncertainty measure.

$$p(y | x) = N(\mu_y, \sigma^2_y)$$

↑ decision models to suggest where to sample next.

Gaussian process: class of functions that have a common feature in terms of continuity

$$P(f) = 0.5$$

poly(f(x)) is high.

⇒ vector based approach → likelihoods (MAE, MAP) fit GPs.